

Appl. No. 10/788,749
Amdt. Dated: May 5, 2006
Reply to Office Action of February 14, 2006

Amendments to the Abstract:

Please replace the abstract of the invention with the following new abstract:

A method for ~~measuring area density of evaluating~~ pattern-dots (14) for a light guide plate (10) includes the steps of: defining ~~[[a]]~~an x-y coordinate system according to the dots; selecting a unit area (142) in the coordinate system; accounting area of the dots in the unit area; ~~and calculating an~~ area density of the dots; and evaluating the optical characteristics of the output light of the light guide plate based upon the calculated area density of the pattern-dots. Quantity of the dots in each unit area is invariable ~~invariableness~~, and each area of each dot-dot in a respective ~~the unit area is~~ has ~~a uniform area.~~ It is convenient to ~~measuring area density of evaluate~~ pattern-dots for a light guide plate by using this method.